Accepted Manuscript

Title: Measurement of the band gap by reflection electron energy loss spectroscopy

Author: Maarten Vos Sean W. King Benjamin L. French



S0368-2048(16)30092-5 http://dx.doi.org/doi:10.1016/j.elspec.2016.08.001 ELSPEC 46579
Journal of Electron Spectroscopy and Related Phenomena
1-5-2016 7-8-2016 11-8-2016

Please cite this article as: Maarten Vos, Sean W. King, Benjamin L. French, Measurement of the band gap by reflection electron energy loss spectroscopy, <*![CDATA[Journal of Electron Spectroscopy and Related Phenomena]]>* (2016), http://dx.doi.org/10.1016/j.elspec.2016.08.001

This is a PDF file of an unedited manuscript that has been accepted for publication. As a service to our customers we are providing this early version of the manuscript. The manuscript will undergo copyediting, typesetting, and review of the resulting proof before it is published in its final form. Please note that during the production process errors may be discovered which could affect the content, and all legal disclaimers that apply to the journal pertain.

ACCEPTED MANUSCRIPT

Semiconductors are measured (without surface preparation) using REELS At low beam energies it is difficult to measure band gap due to surface impurities At very high energies it is difficult to measure band gap due to recoil effect At intermediate energies (around 5 keV) one obtains a good estimate of the band gap Download English Version:

https://daneshyari.com/en/article/5395485

Download Persian Version:

https://daneshyari.com/article/5395485

Daneshyari.com